

FAIRCHILD

SEMICONDUCTOR

August 2001 Revised December 2001 IN1032 3.3V LVDS 4-Bit High Speed Differential Receiver

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FIN1032 3.3V LVDS 4-Bit High Speed Differential Receiver

General Description

This quad receiver is designed for high speed interconnect utilizing Low Voltage Differential Signaling (LVDS) technology. The receiver translates LVDS levels, with a typical differential input threshold of 100mV, to LVTTL signal levels. LVDS provides low EMI at ultra low power dissipation even at high frequencies. This device is ideal for high speed transfer of clock and data.

The FIN1032 can be paired with its companion driver, the FIN1031, or any other Fairchild LVDS driver.

Features

- Greater than 400Mbs data rate
- 3.3V power supply operation
- 0.4ns maximum differential pulse skew
- 2.5ns maximum propagation delay
- Low power dissipation
- Power OFF protection
- Fail safe protection for open-circuit, shorted and terminated conditions
- Meets or exceeds the TIA/EIA-644 LVDS standard
- Pin compatible with equivalent RS-422 and LVPECL devices
- 16-Lead SOIC and TSSOP packages save space

Ordering Code:

Order Number	Package Number	r Package Description			
FIN1032M	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow			
FIN1032MTC MTC16 16-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide					
Devices also available in Tape and Real. Specify by appending the suffix letter "Y" to the ordering code					

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Function Table

	Inputs				
EN	EN R _{IN+}		R _{OUT-}	R _{OUT}	
Н	Х	Н	L	Н	
Н	Х	L H Fail Safe Condition H L		L. L.	
Н	Х			Н	
Х	L			Н	
Х	L	L	Н	L	
Х	L	Fail Safe Condition X		Н	
L	Н			Z	

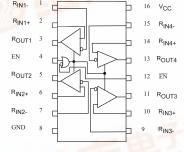
 $H = HIGH \ Logic \ Level \\ Z = High \ Impedance \\ Fail \ Safe = Open, \ Shorted, \ Terminated$

Pin Descriptions

Pin Name	Description
R _{OUT1} , R _{OUT2} , R _{OUT3} , R _{OUT4}	LVTTL Data Outputs
R _{IN1+} , R _{IN2+} , R _{IN3+} , R _{IN4+}	Non-Inverting LVDS Inputs
R _{IN1-} , R _{IN2-} , R _{IN3-} , R _{IN4-}	Inverting LVDS Inputs
EN	Driver Enable Pin
EN	Inverting Driver Enable Pin
V _{CC}	Power Supply
GND	Ground



Connection Diagram



Absolute Maximum Ratings(Note 1)

Supply Voltage (V _{CC})	$-0.5 V$ to $+4.6 \ V$
DC Input Voltage (V _{IN})	-0.5V to +4.6 V
DC Input Voltage (V _{OUT})	-0.5V to 6 V
DC Output Current (I _O)	16 mA
Storage Temperature Range (T _{STG})	-65°C to +150°C
Max Junction Temperature (T _J)	150°C
Lead Temperature (T _L)	
(Soldering, 10 seconds)	260°C
ESD (Human Body Model)	≥ 10,000 V
ESD (Machine Model)	≥ 500 V

Recommended Operating Conditions

Supply Voltage (V _{CC})	3.0 V to 3.6 V			
Magnitude of Differential Voltage				
(V _{ID})	100 mV to V_{CC}			
Common-Mode Input Voltage (VIC)	0.05 V to 2.35V			
Input Voltage (V _{IN})	0 to V_{CC}			
Operating Temperature (T _A)	$-40^{\circ}C$ to $+85^{\circ}C$			
Note 1: The "Absolute Maximum Ratings": are those values beyond which damage to the device may occur. The databack specifications should be				

damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature and output/input loading variables. Fairchild does not recommend operation of circuits outside databook specification.

DC Electrical Characteristics

Over supply voltage and operating temperature ranges, unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ (Note 2)	Max	Units
V _{TH}	Differential Input Threshold HIGH	See Figure 1 and Table 1			100	mV
V _{TL}	Differential Input Threshold LOW	See Figure 1 and Table 1	-100			mV
I _{IN}	Input Current	$V_{IN} = 0V \text{ or } V_{CC}$			±20	μA
I _{I(OFF)}	Power-OFF Input Current	$V_{CC} = 0V, V_{IN} = 0V \text{ or } 3.6V$			±20	μA
VIH	Input High Voltage (EN or EN)		2.0		V _{CC}	V
VIL	Input Low Voltage (EN or EN)		GND		0.8	V
V _{OH}	Output HIGH Voltage	$I_{OH} = -100 \ \mu A$	V _{CC} -0.2			v
		$I_{OH} = -8 \text{ mA}$	2.4			v
V _{OL}	Output LOW Voltage	I _{OH} = 100 μA			0.2	v
		I _{OL} = 8 mA			0.5	v
V _{IK}	Input Clamp Voltage	$I_{IK} = -18 \text{ mA}$	-1.5			V
I _{OZ}	Disabled Output Leakage Current	$EN = 0.8$ and $\overline{EN} = 2V$, $V_{OUT} = 3.6V$ or $0V$			±20	μA
los	Output Short Circuit Test	Receiver Enabled, V _{OUT} = 0V	-15	-100	100	mA
		(one output shorted at a time)	-15	-15		IIIA
I _{CCZ}	Disabled Power Supply Current	Receiver Disabled			5	mA
Icc	Power Supply Current	Receiver Enabled, ($R_{IN+} = 1V$ and $R_{IN-} = 1.4V$)			15	mA
		or ($R_{IN+} = 1.4V$ and $R_{IN-} = 1V$)			15	IIIA
I _{PU/PD}	Output Power Up/Power Down	$V_{CC} = 0V$ to 1.5V			±20	μA
	High Z Leakage Current					
C _{IN}	Input Capacitance			3.5		pF
COUT	Output Capacitance			6		pF

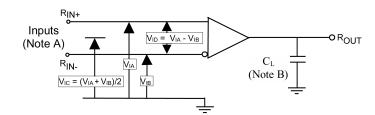
Note 2: All typical values are at $T_A=25^\circ C$ and with $V_{CC}=3.3 V.$

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Symbol	Parameter	Test Conditions	Min	Typ (Note 3)	Max	Units
t _{PLH}	Propagation Delay LOW-to-HIGH		1.0		2.5	ns
t _{PHL}	Propagation Delay HIGH-to-LOW	1	1.0		2.5	ns
t _{TLH}	Output Rise Time (20% to 80%)	$ V_{ID} = 400 \text{ mV}, C_L = 10 \text{ pF},$		0.7	1.2	ns
t _{THL}	Output Fall Time (80% to 20%)	$R_L = 1k\Omega$		0.7	1.2	ns
t _{SK(P)}	Pulse Skew t _{PLH} - t _{PHL}	See Figure 1 and Figure 2			0.4	ns
t _{SK(LH)}	Channel-to-Channel Skew	1			0.3	ns
t _{SK(HL)}	(Note 4)				0.3	ns
t _{SK(PP)}	Part-to-Part Skew (Note 5)	1			1.0	ns
f _{MAX}	Maximum Operating Frequency (Note 6)	$R_L = 1k\Omega$, $C_L = 10 \text{ pF}$, see Figure 1 and Figure 2	200	325		MHz
t _{ZH}	LVTTL Output Enable Time from Z to HIGH				5.0	ns
t _{ZL}	LVTTL Output Enable Time from Z to LOW	$R_L = 1k\Omega$, $C_L = 10 \text{ pF}$,			5.0	ns
t _{HZ}	LVTTL Output Disable Time from HIGH to Z	See Figure 3 and Figure 4			5.0	ns
t _{LZ}	LVTTL Output Disable Time from LOW to Z	1			5.0	ns

Note 4: $t_{SK(LH)}$, $t_{SK(HL)}$ is the skew between specified outputs of a single device when the outputs have identical loads and are switching in the same direction.

Note 5: $t_{SK(PP)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices switching in the same direction (either LOW-to-HIGH or HIGH-to-LOW) when both devices operate with the same supply voltage, same temperature, and have identical test circuits. Note 6: f_{MAX} Criteria: Input $t_R = t_F < 1$ ns, $V_{ID} = 300$ mV, (1.05V to 1.35V pp), 50% duty cycle; Output duty cycle 40% to 60%, $V_{OL} < 0.5V$, $V_{OH} > 2.4V$. All channels switching in phase.



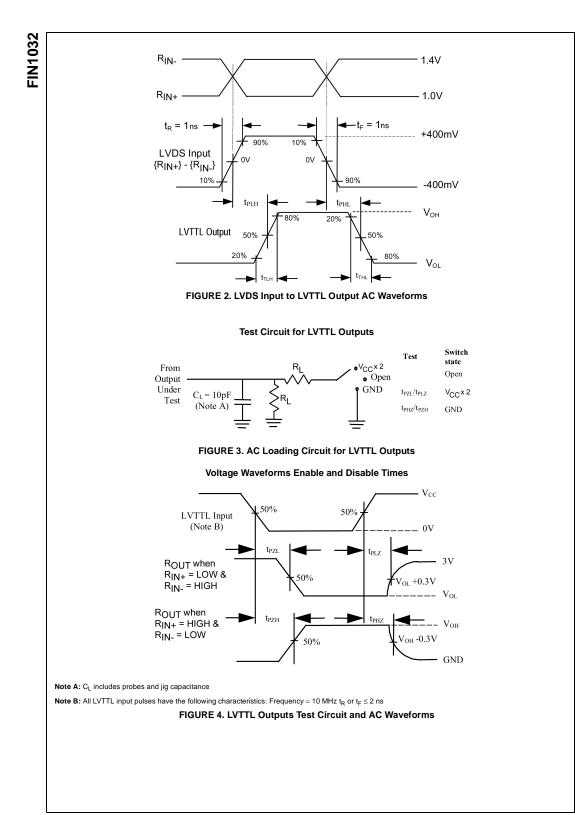
Note A: All input pulses have frequency = 10MHz, t_R or t_F = 1ns

AC Electrical Characteristics

Note B: C_L includes all probe and jig capacitances

FIGURE 1. Differential Receiver Voltage Definitions and Propagation Delay and Transition Time Test Circuit

Applied \	/oltages (V)	Resulting Differential Input	Resulting Common Mode Input		
		Voltage (mA)	Voltage (V)		
V _{IA}	V _{IB}	V _{ID}	V _{IC}		
1.25	1.15	100	1.2		
1.15	1.25	-100	1.2		
2.4	2.3	100	2.35		
2.3	2.4	-100	2.35		
0.1	0	100	0.05		
0	0.1	-100	0.05		
1.5	0.9	600	1.2		
0.9	1.5	-600	1.2		
2.4	1.8	600	2.1		
1.8	2.4	-600	2.1		
0.6	0	600	0.3		
0	0.6	-600	0.3		



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